

Notice of References Cited	Application/Control No. 10/511,571	Applicant(s)/Patent Under Reexamination FEWSTER, PAUL FREDERICK	
	Examiner Jurie Yun	Art Unit 2882	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,970,532	11-2005	Hayashi et al.	378/79
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Noma et al., 'Surface-Sensitive X-ray Fluorescence and Diffraction Analysis with Grazing-Exit Geometry' X-RAY SPECTROMETRY, vol. 28, 1999, pages 433-439
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.